


<b>Search Notes</b>  	<b>Application/Control No.</b>  10528739	<b>Applicant(s)/Patent Under Reexamination</b>  SENESCHAL ET AL.
	<b>Examiner</b>  RICHARD CHAN	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
455	71, 203, 46, 202, 265	12/20/08	RC

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner

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